









SN65LBC174A, SN75LBC174A

SLLS446G - OCTOBER 2000 - REVISED APRIL 2024

SNx5LBC174A Quadruple RS-485 Differential Line Drivers

1 Features

- Designed for TIA/EIA-485, TIA/EIA-422 and ISO 8482 applications
- Signaling Rates ¹up to 30 Mbps
- Propagation delay times < 11ns
- Low standby power consumption 1.5mA max
- Output ESD protection: 12kV
- Driver positive- and negative-current limiting
- Power-up and power-down glitch-free for line insertion applications
- Thermal shutdown protection
- Industry standard pin-out, compatible With SN75174, MC3487, DS96174, LTC487, and MAX3042

2 Applications

- Motor drives
- Factory automation and control

3 Description

SN65LBC174A SN75LBC174A The and quadruple differential line drivers with 3-state outputs. designed for TIA/EIA-485 (RS-485), TIA/EIA-422 (RS-422), and ISO 8482 applications.

These devices are optimized for balanced multipoint bus transmission at signaling rates up to 30 million bits per second. The transmission media may be printed-circuit board traces, backplanes, or cables.

The ultimate rate and distance of data transfer is dependent upon the attenuation characteristics of the media and the noise coupling to the environment.

Each driver features current limiting and thermalshutdown circuitry making it suitable for high-speed multipoint applications in noisy environments. These devices are designed using LinBiCMOS®, facilitating low power consumption and robustness.

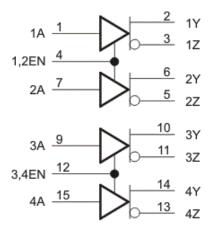
The two EN inputs provide pair-wise driver enabling, or can be externally tied together to provide enable control of all four drivers with one signal. When disabled or powered off, the driver outputs present a high-impedance to the bus for reduced system loading.

The SN75LBC174A is characterized for operation over the temperature range of 0°C to 70°C. The SN65LBC174A is characterized for operation over the temperature range of -40°C to 85°C.

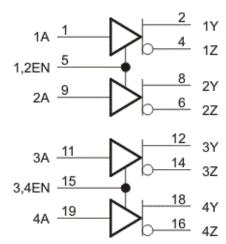
Package Information

PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE ⁽²⁾		
0.1051.50.454.	SOIC (DW, 16)	10.3mm × 10.3mm		
SN65LBC174A SN75LBC174A	SOIC (DW, 20)	12.8mm × 10.3mm		
OIV/OLDO I/ 4/A	PDIP (N, 16)	19.3mm × 9.4mm		

- (1) For more information, see Section 11.
- The package size (length × width) is a nominal value and includes pins, where applicable.



Logic Diagram (Positive Logic)



Logic Diagram (Positive Logic)

¹ The signaling rate of a line is the number of voltage transitions that are made per second expressed in the units bps (bits per second).

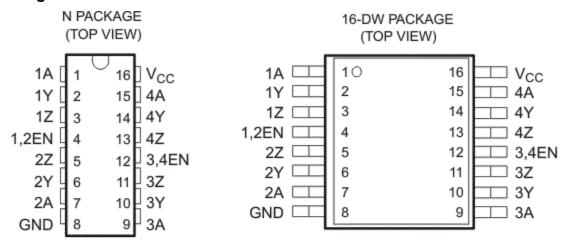


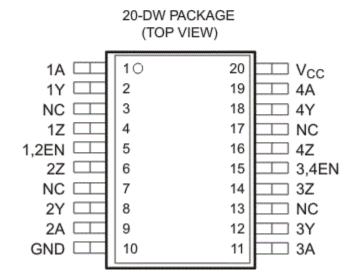
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4 Pin Configuration and Functions





5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			VALUE / UNIT
Supply voltage rar	Supply voltage range, V _{CC} ⁽²⁾		–0.3 V to 6 V
Voltage range at a	ny bus (DC)	–10 V to 15 V	
Voltage range at any bus (transient pulse through 100 Ω , see Figure 6-8)		–30 V to 30 V	
Input voltage range	Input voltage range at any A or EN terminal, V _I		–0.5 V to V _{CC} + 0.5 V
	Lluman hady model (3)	Y, Z, and GND	±12 kV
Electrostatic discharge	Human body model ⁽³⁾	All pins	±5 kV
discritings	Charged-device model (4)	All pins	±1 kV
Storage temperature range, T _{stg}		−65°C to 150°C	
Continuous power dissipation		See Dissipation Rating Table	

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- (2) All voltage values, except differential I/O bus voltages, are with respect to GND.
- (3) Tested in accordance with JEDEC standard 22, Test Method A114-A.
- (4) Tested in accordance with JEDEC standard 22, Test Method C101.

5.2 Dissipation Rating Table

Table 5-1. Dissipation Rating Table

PACKAGE ⁽¹⁾	JEDEC BOARD MODEL	T _A ≤ 25°C POWER RATING	DERATING FACTOR (2) ABOVE T _A = 25°C	T _A = 70°C POWER RATING	T _A = 85°C POWER RATING
16 DW	LOW K	1200 mW	9.6 mW/°C	769 mW	625 mW
I DVV	HIGH K	2240 mW	17.9 mW/°C	1434 mW	1165 mW
20 DW	LOW K	1483 mW	11.86 mW/°C	949 mW	771 mW
20 DVV	HIGH K	2753 mW	22 mW/°C	1762 mW	1432 mW
16 N	LOW K	1150 mW	9.2 mW/°C	736 mW	598 mW

⁽¹⁾ For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.

5.3 Recommended Operating Conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}		4.75	5	5.25	V
Voltage at any bus terminal	Y, Z	-7		12	V
High-level input voltage, V _{IH}	A. EN	2		V _{CC}	\/
Low-level input voltage, V _{IL}	A, LN	0		0.8	V
Output current		-60		60	mA
Operating free-air	SN75LBC174A	0		70	°C
temperature, T _A	SN65LBC174A	-40		85	

⁽²⁾ This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.



5.4 Thermal Information

	THERMAL METRIC ⁽¹⁾	N (PDIP)	DW (SOIC)	DW	UNIT
		16 PINS	16 PINS	20 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	60.6	71.1	66.8	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	48.1	37.4	34.4	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	40.6	36.8	39.7	°C/W
ΨЈТ	Junction-to-top characterization parameter	27.5	13.3	8.9	°C/W
ΨЈВ	Junction-to-board characterization parameter	40.3	36.4	39	°C/W
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	n/a	n/a	n/a	°C/W

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

5.5 Electrical Characteristics

over recommended operating conditions

	PARAMETER	TEST CONI	TEST CONDITIONS			MAX	UNIT
V _{IK}	Input clamp voltage	I _I = -18 mA		-1.5	-0.77		V
Vo	Open-circuit output voltage	Y or Z, No load		0		V _{CC}	V
		No load (open circuit)		3		V _{CC}	
$ V_{OD(SS)} $	Steady-state differential output voltage magnitude ⁽²⁾	$R_L = 54\Omega$, See Figure 6-1		1	1.6	2.5	V
	maginiado	With common-mode loading	ng, See Figure 6-2	1	1.6	2.5	
$\Delta V_{OD(SS)}$	Change in steady-state differential output voltage between logic states	See Figure 6-1	-0.1		0.1	٧	
V _{OC(SS)}	Steady-state common-mode output voltage	See Figure 6-3	2	2.4	2.8	V	
$\Delta V_{OC(SS)}$	Change in steady-state common-mode output voltage between logic states	See Figure 6-3	-0.02		0.02	V	
I _I	Input current	A, EN		-50		50	μA
	Short circuit output current		V _I = 0V	-200		200	mA
los	Short-circuit output current	V _{TEST} = -7V to 12V, See	V _I = V _{CC}	-200		200	
l _{OZ}	High-impedance-state output current	Figure 6-7	EN at 0V	-50		50	
I _{O(OFF)}	Output current with power off		V _{CC} = 0V	-10		10	μA
	Cumply ourrent	\/ = 0\/ or \/ No load	All drivers enabled			23	mA
I _{CC} Supply current		V _I = 0V or V _{CC,} No load All drivers disabled				1.5	MA
C	Input Capacitance	A inputs			13		pF
C _{IN}	при Сараспапсе	EN inputs			21		pF

⁽¹⁾ All typical values are at V_{CC} = 5V and 25°C.

5.6 Switching Characteristics

over recommended operating conditions

PARAI	METER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	Propagation delay time, low-to-high level output		5.5	8	11	ns
t _{PHL}	Propagation delay time, high-to-low level output		5.5	8	11	ns
t _r	Differential output voltage rise time		2	7.5	11	ns
t _f	Differential output voltage fall time	$R_L = 54\Omega, C_L = 50pF,$	2	7.5	11	ns
	Dulas alsouds & I	See Figure 6-4		0.6	2	
t _{sk(p)}	Pulse skew t _{PLH} - t _{PHL}			0.6	2	ns
t _{sk(o)}	Output skew ⁽¹⁾				2	ns
t _{sk(pp)}	Part-to-part skew ⁽²⁾				3	ns
t _{PZH}	Propagation delay time, high-impedance-to-high-level output	See Figure 6-5			25	ns
t _{PHZ}	Propagation delay time, high-level-output-to-high impedance	See Figure 0-5			25	ns
t _{PZL}	Propagation delay time, high-impedance-to-low-level output	See Figure 6-6			30	ns
t _{PLZ}	Propagation delay time, low-level-output-to-high impedance	See Figure 0-0			20	ns

⁽¹⁾ Output skew (t_{sk(o)}) is the magnitude of the time delay difference between the outputs of a single device with all of the inputs connected together.

⁽²⁾ The minimum V_{OD} may not fully comply with TIA/EIA-485-A at operating temperatures below 0°C. System designers should take the possibly lower output signal into account in determining the maximum signal transmission distance.

⁽²⁾ Part-to-part skew (t_{sk(pp)}) is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same input signals, the same supply voltages, at the same temperature, and have identical packages and test circuits.



5.7 Typical Characteristics

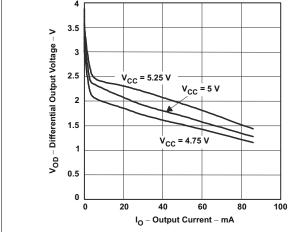


Figure 5-1. Differential Output Voltage vs Output Current

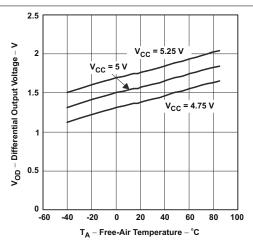


Figure 5-2. Differential Output Voltage vs Free-air Temperature

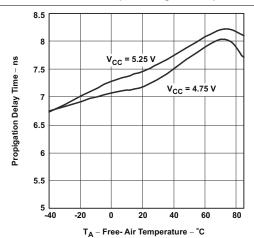


Figure 5-3. Propagation Delay Time vs Free-air Temperature

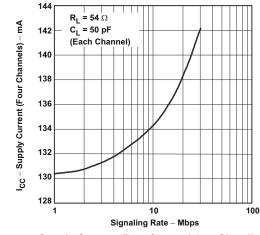
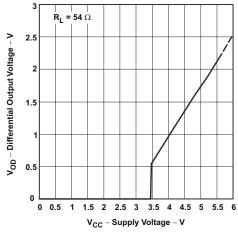
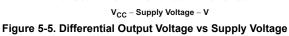
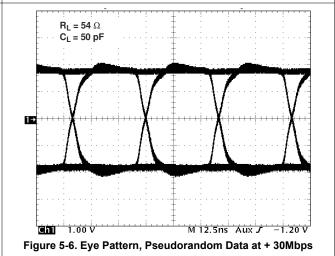


Figure 5-4. Supply Current (Four Channels) vs Signaling Rate









6 Parameter Measure Information

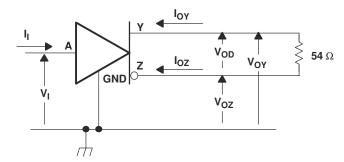


Figure 6-1. Test Circuit, V_{OD} Without Common-Mode Loading

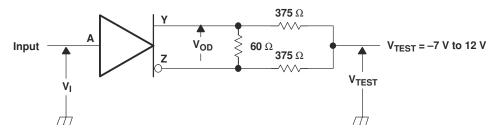
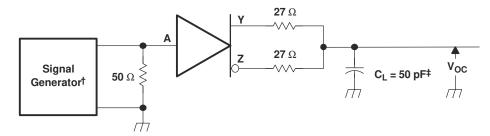
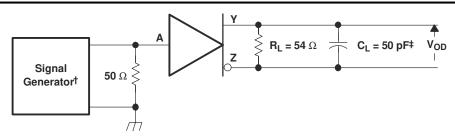


Figure 6-2. Test Circuit, V_{OD} With Common-Mode Loading



- † PRR = 1 MHz, 50% Duty Cycle, t_r < 6 ns, t_f < 6 ns, Z_O = 50 Ω
- ‡ Includes probe and jig capacitance

Figure 6-3. V_{OC} Test Circuit



- † PRR = 1 MHz, 50% Duty Cycle, t_{r} < 6 ns, t_{f} < 6 ns, Z_{O} = 50 Ω
- [‡] Includes probe and jig capacitance

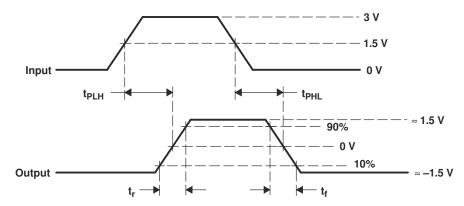
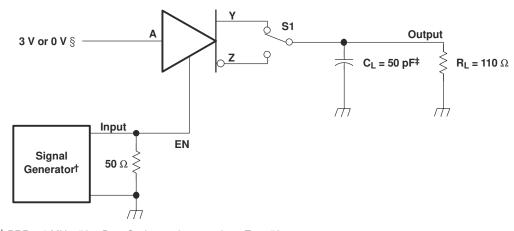


Figure 6-4. Output Switching Test Circuit and Waveforms





- † PRR = 1 MHz, 50% Duty Cycle, t_r < 6 ns, t_f < 6 ns, Z_O = 50 Ω
- ‡ Includes probe and jig capacitance
- § 3 V if testing Y output, 0 V if testing Z output

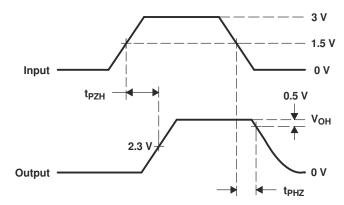
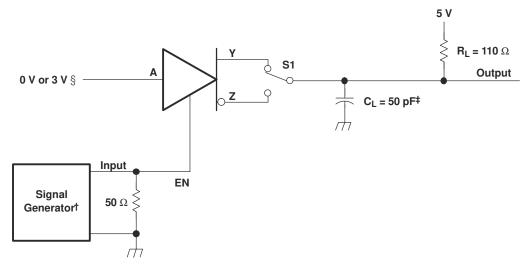


Figure 6-5. Enable Timing Test Circuit and Waveforms, t_{PZH} and t_{PHZ}



- † PRR = 1 MHz, 50% Duty Cycle, t_{r} < 6 ns, t_{f} < 6 ns, Z_{O} = 50 Ω
- ‡ Includes probe and jig capacitance
- § 3 V if testing Y output, 0 V if testing Z output

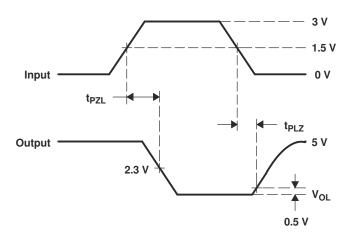


Figure 6-6. Enable Timing Test Circuit and Waveforms, t_{PZL} and t_{PLZ}



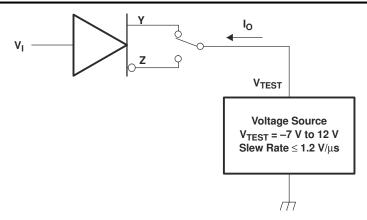


Figure 6-7. Test Circuit, Short-Circuit Output Current

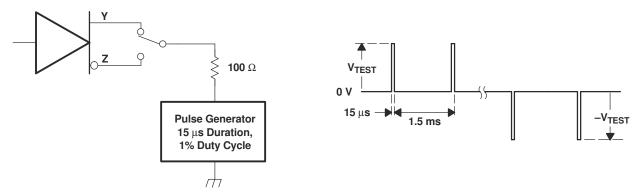


Figure 6-8. Test Circuit Waveform, Transient Overvoltage Test

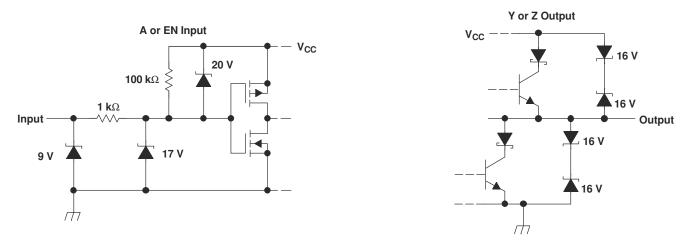


Figure 6-9. Equivalent Input and Output Schematic Diagrams



7 Device Functional Modes

Table 7-1. Function table (each driver)

INPUT ⁽¹⁾	ENABLE	OUTPUT	OUTPUT
Α	EN	Y	Z
L	Н	L	Н
Н	Н	Н	L
OPEN	Н	Н	L
L	OPEN	L	Н
Н	OPEN	Н	L
OPEN	OPEN	Н	L
X	L	Z	Z

⁽¹⁾ H = high level, L = low level, X = irrelevant, Z = high impedance (off)

8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

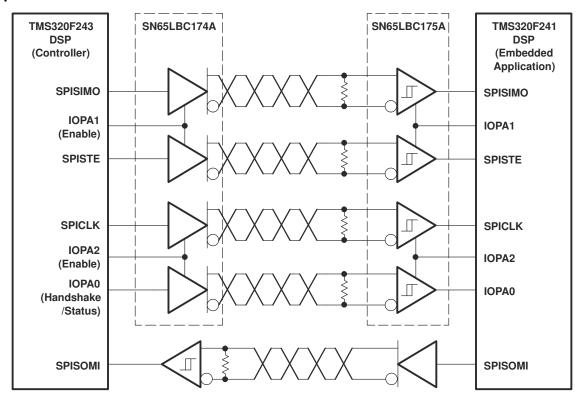


Figure 8-1. Typical Application Circuit, DSP-to-DSP Link via Serial Peripheral Interface



9 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

9.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.2 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

9.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

LinBiCMOS® is a registered trademark of Texas Instruments.

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9.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision F (October 2009) to Revision G (April 2024)	Page
Changed the numbering format for tables, figures, and cross-references throughout the doc	ument1
Added the Thermal Information table	5
	_
Changes from Revision E (July 2008) to Revision F (October 2009)	Page
Added C _{IN} - Input Capacitance to the Electrical Characteristics table	6
Changed the location of Figure 6-9	8
Changed Table 7-1 header From: ENABLE G To: ENABLE EN	
Changes from Revision D (June 2008) to Revision E (July 2008)	Page

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Changes from Revision C (June 2008) to Revision D (July 2008)	Page
Changed Electrostatic discharge-Human body model-Y, Z, and GND From: 13kV To: 11kV	
Changed the Dissipation Rating Table	4
Changes from Revision B (June 2001) to Revision C (May 2003)	Page
 Changed Features bullet From: Output ESD Protection Exceeds 13 kV To: Output ESD Protect 	
 Changed Features bullet for Industry Standard From: Compatible With SN75174, MC3487, and 	
Compatible With SN75174, MC3487, DS96174, LTC487, and MAX3042	
Changes from Revision A (February 2001) to Revision B (June 2001)	Page
Changed DW Package appearance	
Added Figure 5-5	7
Changes from Revision * (October 2000) to Revision A (February 2001)	Page
Changed multiple items throughout the data sheet	1

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Submit Document Feedback

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8-Nov-2025

PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
		. ,				(4)	(5)		
SN65LBC174A16DW	Obsolete	Production	SOIC (DW) 16	-	-	Call TI	Call TI	-40 to 85	65LBC174A
SN65LBC174A16DWR	Active	Production	SOIC (DW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	65LBC174A
SN65LBC174A16DWR.A	Active	Production	SOIC (DW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	65LBC174A
SN65LBC174A16DWRG4	Active	Production	SOIC (DW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	65LBC174A
SN65LBC174ADW	Obsolete	Production	SOIC (DW) 20	-	-	Call TI	Call TI	-40 to 85	65LBC174A
SN65LBC174ADWR	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	65LBC174A
SN65LBC174ADWR.A	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	65LBC174A
SN65LBC174AN	Active	Production	PDIP (N) 16	25 TUBE	Yes	NIPDAU	N/A for Pkg Type	-40 to 85	65LBC174A
SN65LBC174AN.A	Active	Production	PDIP (N) 16	25 TUBE	Yes	NIPDAU	N/A for Pkg Type	-40 to 85	65LBC174A
SN75LBC174A16DW	Obsolete	Production	SOIC (DW) 16	-	-	Call TI	Call TI	0 to 70	75LBC174A
SN75LBC174A16DWR	Obsolete	Production	SOIC (DW) 16	-	-	Call TI	Call TI	0 to 70	75LBC174A
SN75LBC174ADW	Active	Production	SOIC (DW) 20	25 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	75LBC174A
SN75LBC174ADW.A	Active	Production	SOIC (DW) 20	25 TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	75LBC174A
SN75LBC174ADWR	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	75LBC174A
SN75LBC174ADWR.A	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	75LBC174A
SN75LBC174AN	Obsolete	Production	PDIP (N) 16	-	-	Call TI	Call TI	0 to 70	75LBC174A

⁽¹⁾ Status: For more details on status, see our product life cycle.

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

PACKAGE OPTION ADDENDUM

www.ti.com 8-Nov-2025

(6) Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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OTHER QUALIFIED VERSIONS OF SN65LBC174A:

Enhanced Product : SN65LBC174A-EP

NOTE: Qualified Version Definitions:

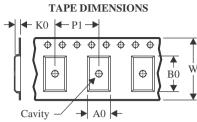
• Enhanced Product - Supports Defense, Aerospace and Medical Applications

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65LBC174A16DWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
SN65LBC174ADWR	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
SN75LBC174ADWR	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1

PACKAGE MATERIALS INFORMATION

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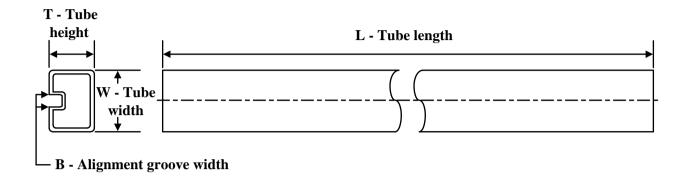
*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN65LBC174A16DWR	SOIC	DW	16	2000	350.0	350.0	43.0
SN65LBC174ADWR	SOIC	DW	20	2000	356.0	356.0	45.0
SN75LBC174ADWR	SOIC	DW	20	2000	350.0	350.0	43.0

PACKAGE MATERIALS INFORMATION

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TUBE



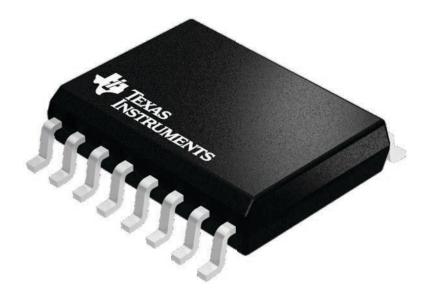
*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
SN65LBC174AN	N	PDIP	16	25	506	13.97	11230	4.32
SN65LBC174AN.A	N	PDIP	16	25	506	13.97	11230	4.32
SN75LBC174ADW	DW	SOIC	20	25	507	12.83	5080	6.6
SN75LBC174ADW	DW	SOIC	20	25	506.98	12.7	4826	6.6
SN75LBC174ADW.A	DW	SOIC	20	25	506.98	12.7	4826	6.6
SN75LBC174ADW.A	DW	SOIC	20	25	507	12.83	5080	6.6

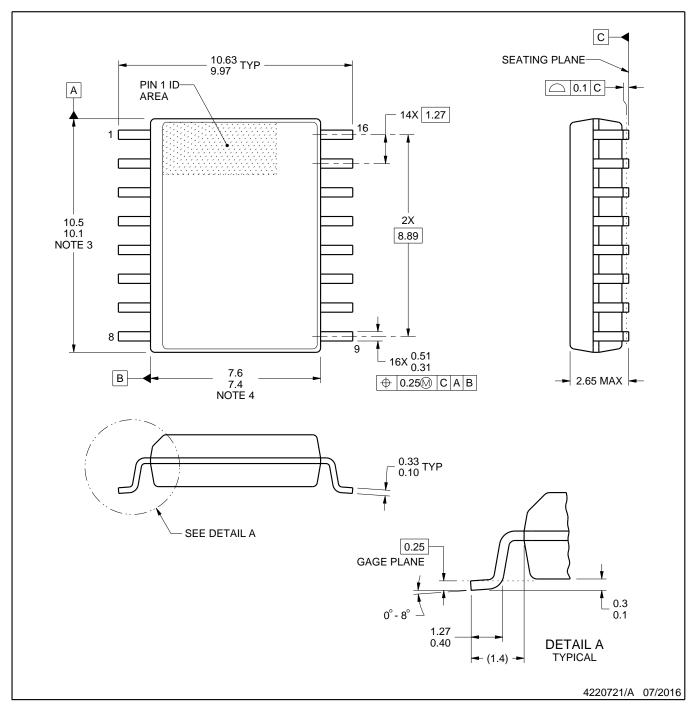
7.5 x 10.3, 1.27 mm pitch

SMALL OUTLINE INTEGRATED CIRCUIT

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.







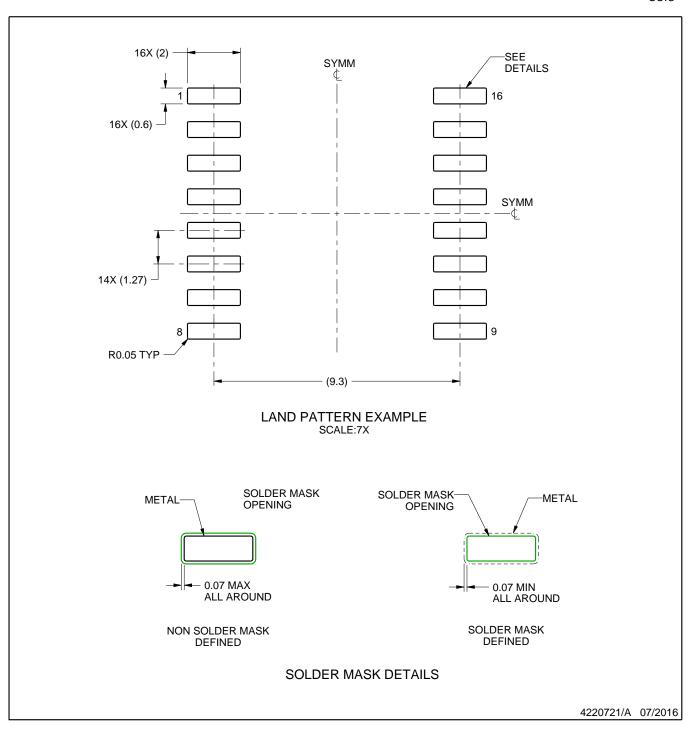
NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing
- per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm, per side.
- 5. Reference JEDEC registration MS-013.



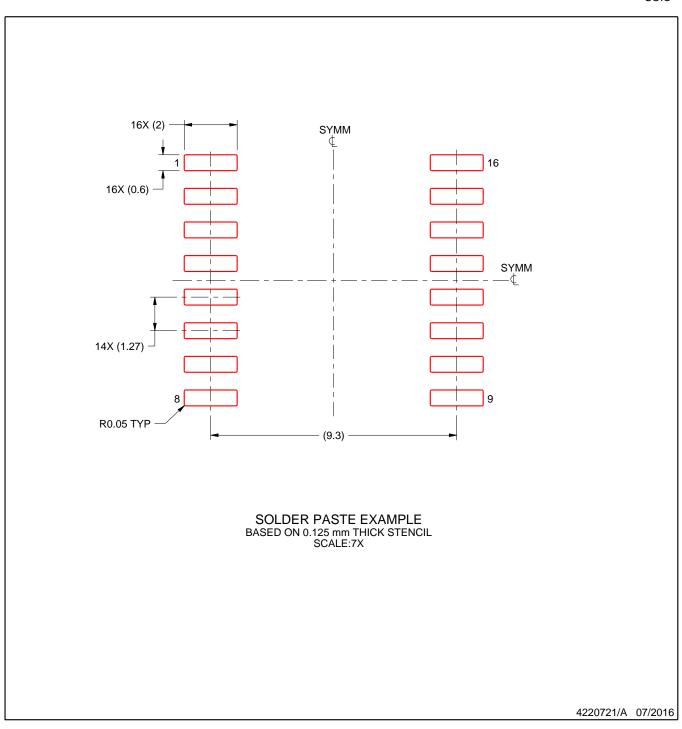


NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN

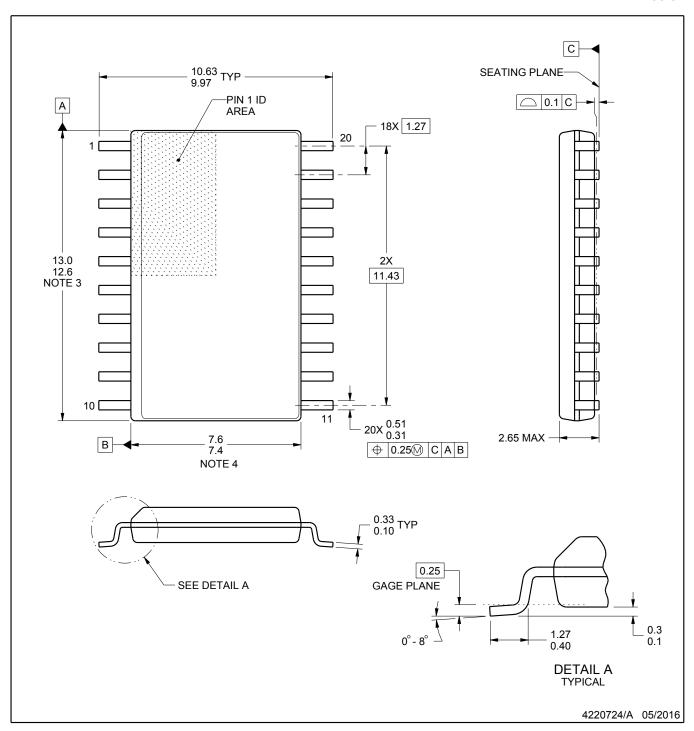


NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.







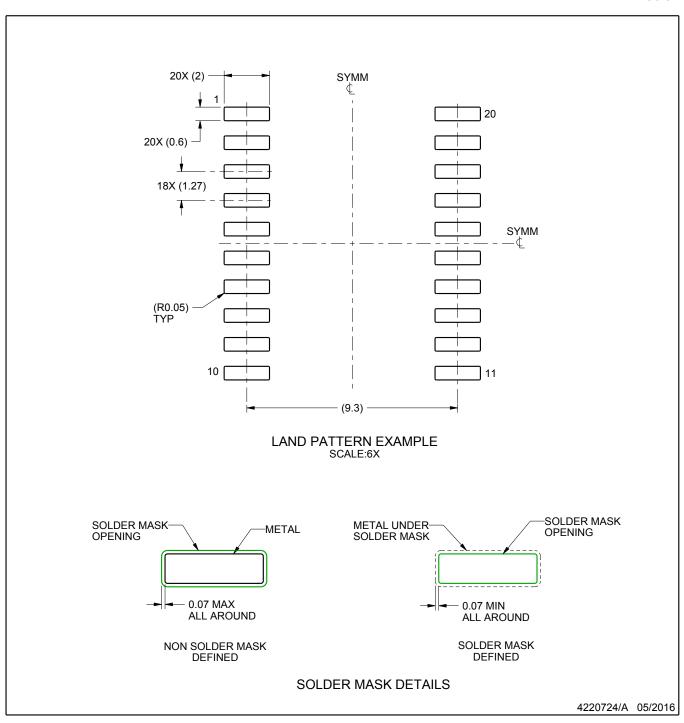
NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



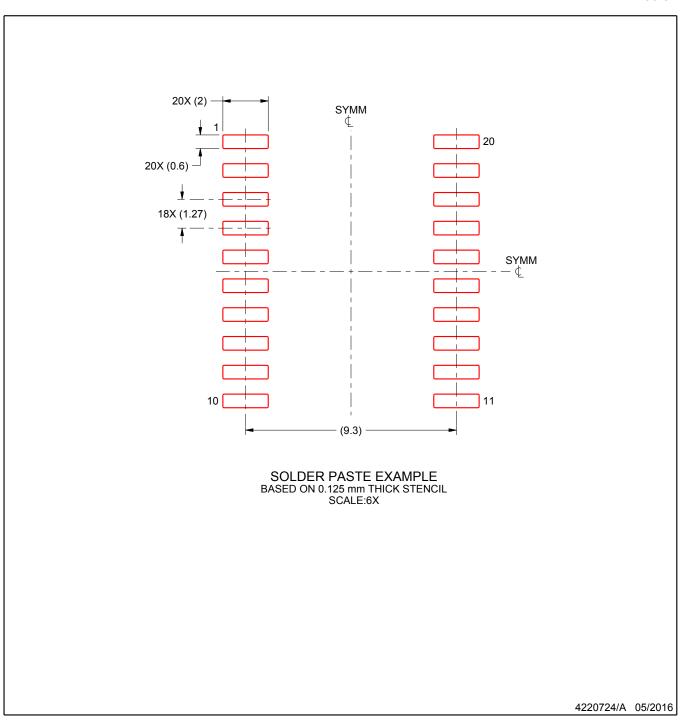


NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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